ON Semiconductor®

FGH75T65UPD-F085
650V, 75A Field Stop Trench IGBT

Features

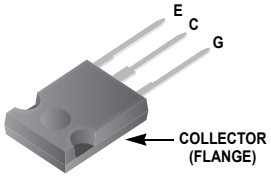
- Maximum Junction Temperature : $T_J = 175^oC$
- Positive Temperaure Co-efficient for easy parallel operating
- High current capability
- Low saturation voltage: $V_{CE(sat)}$ = 1.65V(Typ.) @ I_C = 75A
- High input impedance
- Tightened Parameter Distribution
- RoHS compliant
- Qualified to Automotive Requirements of AEC-Q101

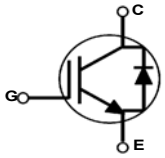
General Description

Using Novel Field Stop Trench IGBT Technology, ON Semiconductor's new series of Field Stop Trench IGBTs offer the optimum perfor-mance for Automotive chargers, Solar Inverter, UPS and Digital Power Generator where low conduction and switching losses are essential.

Applications

- Automotive chargers, Converters, High Voltage Auxiliaries
- Solar Inverters, UPS, Digital Power Generator





Absolute Maximum Ratings

Symbol	Description		Ratings	Units
V_{CES}	Collector to Emitter Voltage		650	V
V_{GES}	Gate to Emitter Voltage		± 20	V
I_C	Collector Current	@ $T_C = 25^oC$	150	A
	Collector Current	@ $T_C = 100^oC$	75	A
$I_{CM\ (1)}$	Pulsed Collector Current		225	A
I_F	Diode Forward Current	@ $T_C = 25^oC$	75	A
	Diode Forward Current	@ $T_C = 100^oC$	50	A
$I_{FM(1)}$	Pulsed Diode Maximum Forward Current		225	A
P_D	Maximum Power Dissipation	@ $T_C = 25^oC$	375	W
	Maximum Power Dissipation	@ $T_C = 100^oC$	187	W
SCWT	Short Circuit Withstand Time	@ $T_C = 25^oC$	5	us
T_J	Operating Junction Temperature		-55 to +175	^oC
T_{stg}	Storage Temperature Range		-55 to +175	^oC
T_L	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	^oC

Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$(IGBT)(2)	Thermal Resistance, Junction to Case	0.4	$^oC/W$
$R_{\theta JC}$(Diode)	Thermal Resistance, Junction to Case	0.86	$^oC/W$

Symbol	Parameter	Typ.	Units
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (PCB Mount)(2)	40	$^oC/W$

September-2017, Rev. 3

Publication Order Number:
FGH75T65UPD-F085/D

Package Marking and Ordering Information

Device Marking	Device	Package	Packing Type	Qty per Tube
FGH75T65UPD	FGH75T65UPD-F085	TO-247	Tube	30ea

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
Off Characteristics						
BV_{CES}	Collector to Emitter Breakdown Voltage	V_{GE} = 0V, I_C = 1mA	650	-	-	V
$\frac{\Delta BV_{CES}}{\Delta T_J}$	Temperature Coefficient of Breakdown Voltage	V_{GE} = 0V, I_C = 1mA	-	0.65	-	V/^oC
I_{CES}	Collector Cut-Off Current	V_{CE} = V_{CES}, V_{GE} = 0V	-	-	250	μA
		I_{CES} at 80%*B_{VCES}, 175^oC	-	-	3600	
I_{GES}	G-E Leakage Current	V_{GE} = V_{GES}, V_{CE} = 0V	-	-	±400	nA
On Characteristics						
$V_{GE(th)}$	G-E Threshold Voltage	I_C = 75mA, V_{CE} = V_{GE}	4.0	6.0	7.5	V
$V_{CE(sat)}$	Collector to Emitter Saturation Voltage	I_C = 75A, V_{GE} = 15V	-	1.69	2.3	V
		I_C = 75A, V_{GE} = 15V, T_C = 175^oC	-	2.21	-	V
Dynamic Characteristics						
C_{ies}	Input Capacitance	V_{CE} = 30V, V_{GE} = 0V, f = 1MHz	-	5665	-	pF
C_{oes}	Output Capacitance		-	205	-	pF
C_{res}	Reverse Transfer Capacitance		-	100	-	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{CC} = 400V, I_C = 75A, R_G = 3Ω, V_{GE} = 15V, Inductive Load, T_C = 25^oC	-	32	48	ns
t_r	Rise Time		-	43	71	ns
$t_{d(off)}$	Turn-Off Delay Time		-	166	216	ns
t_f	Fall Time		-	24	33	ns
E_{on}	Turn-On Switching Loss		-	2.85	4.80	mJ
E_{off}	Turn-Off Switching Loss		-	1.20	1.60	mJ
E_{ts}	Total Switching Loss		-	4.05	5.3	mJ
$t_{d(on)}$	Turn-On Delay Time	V_{CC} = 400V, I_C = 75A, R_G = 3Ω, V_{GE} = 15V, Inductive Load, T_C = 175^oC	-	30	-	ns
t_r	Rise Time		-	57	-	ns
$t_{d(off)}$	Turn-Off Delay Time		-	176	-	ns
t_f	Fall Time		-	21	-	ns
E_{on}	Turn-On Switching Loss		-	4.45	-	mJ
E_{off}	Turn-Off Switching Loss		-	1.60	-	mJ
E_{ts}	Total Switching Loss		-	6.05	-	mJ
Tsc	Short Circuit Withstand Time	V_{GE} = 15V, V_{CC} ≤ 400V, Rg = 10 Ω	5	-	-	us

Notes:

1:Repetitive rating: Pulse width limited by max junction temperature.

2:Rthjc for TO-247 : according to Mil standard 883-1012 test method. Rthja for TO-247 : according to JESD51-2, test method environmental condition and JESD51-10, test boards for through hole perimeter leaded package thermal measurements. JESD51-3 : Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Package.

Electrical Characteristics of the IGBT (Continued)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max	Units
Q_g	Total Gate Charge	V_{CE} = 400V, I_C = 75A, V_{GE} = 15V	-	385	578	nC
Q_{ge}	Gate to Emitter Charge		-	45	68	nC
Q_{gc}	Gate to Collector Charge		-	210	315	nC

Electrical Characteristics of the Diode T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions		Min.	Typ.	Max	Units
V_{FM}	Diode Forward Voltage	I_F = 50A	T_C = 25°C	-	2.1	2.6	V
			T_C = 175°C	-	1.7	-	
E_{rec}	Reverse Recovery Energy	I_F =50A, dI_F/dt = 200A/μs	T_C = 175°C	-	40	-	uJ
t_{rr}	Diode Reverse Recovery Time		T_C = 25°C	-	43	85	ns
			T_C = 175°C	-	162	-	
Q_{rr}	Diode Reverse Recovery Charge		T_C = 25°C	-	83	170	nC
			T_C = 175°C	-	805	-	

Typical Performance Characteristics

Figure 1. Typical Output Characteristics

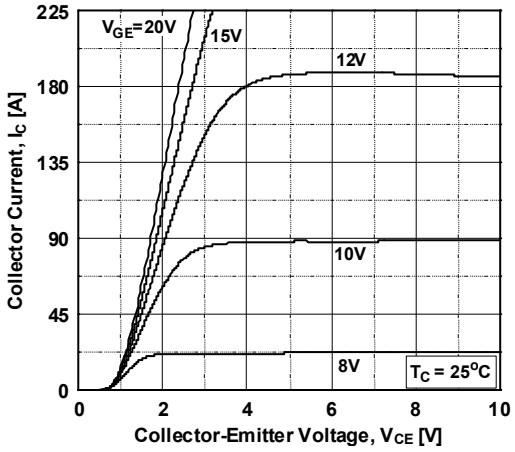


Figure 2. Typical Output Characteristics

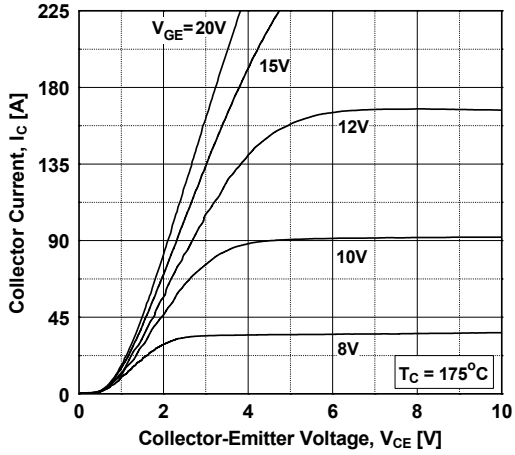


Figure 3. Typical Saturation Voltage Characteristics

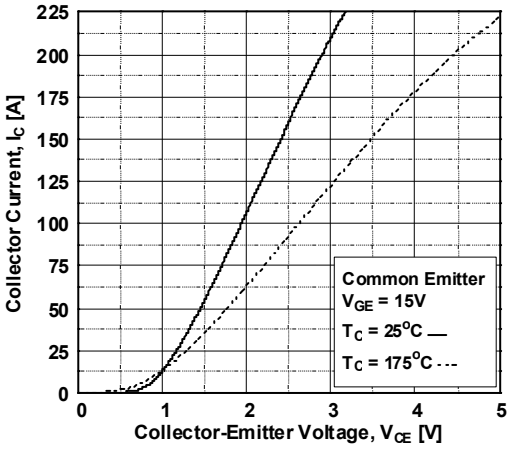


Figure 4. Transfer Characteristics

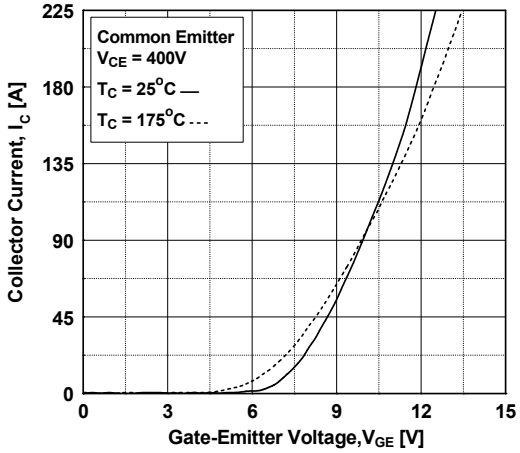


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

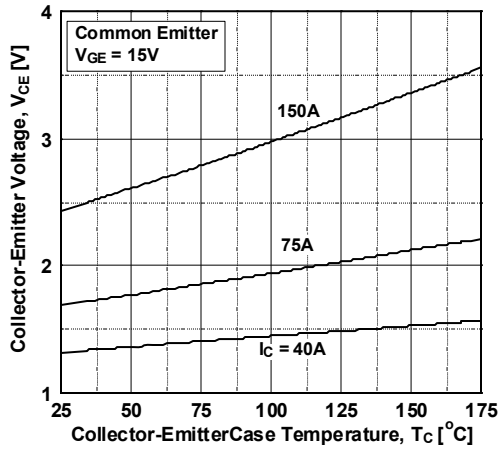
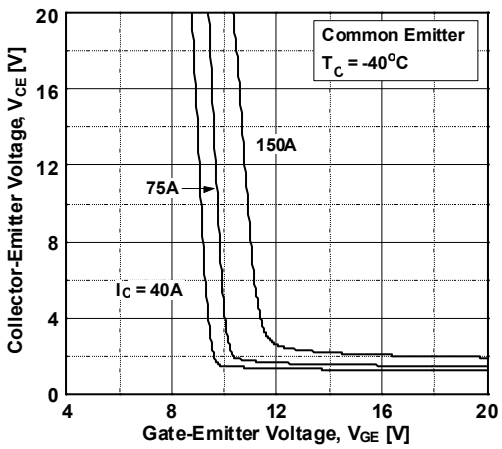


Figure 6. Saturation Voltage vs. V_{GE}



Typical Performance Characteristics

Figure 7. Saturation Voltage vs. V_{GE}

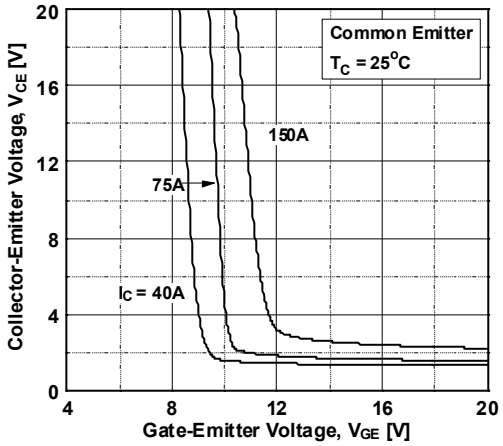


Figure 8. Saturation Voltage vs. V_{GE}

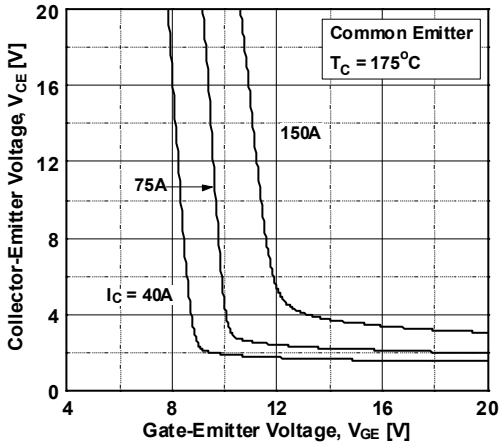


Figure 9. Capacitance Characteristics

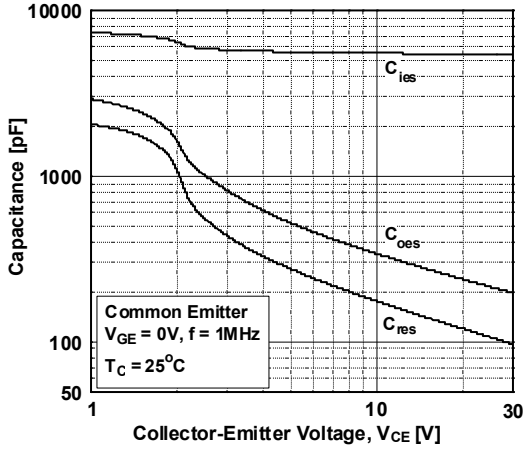


Figure 10. Gate charge Characteristics

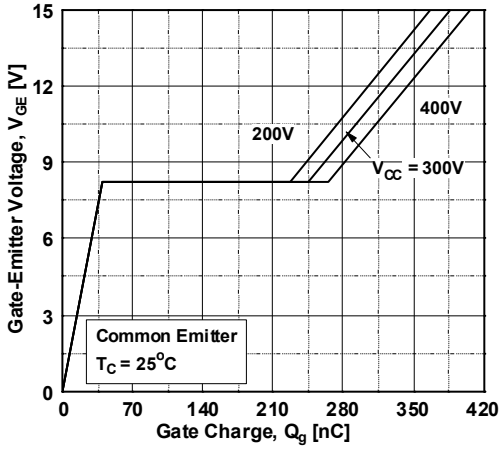


Figure 11. SOA Characteristics

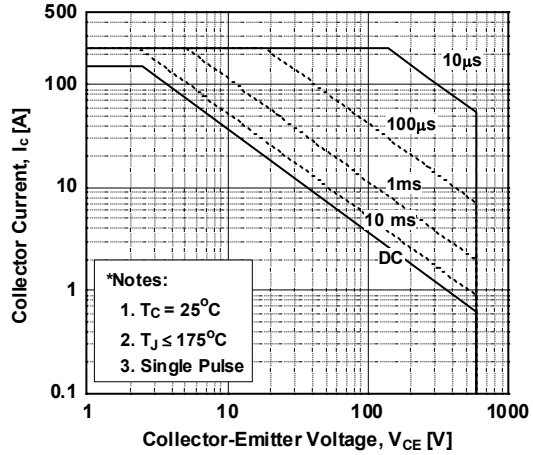
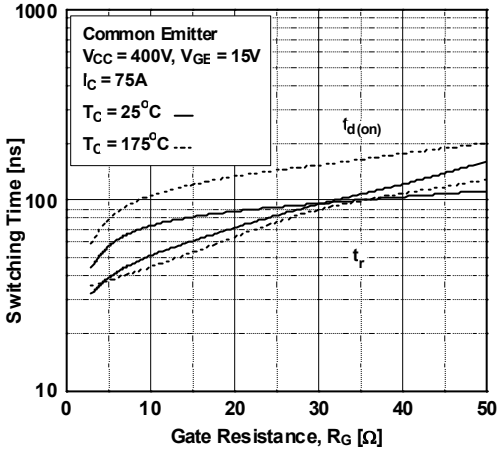


Figure 12. Turn-on Characteristics vs. Gate Resistance



Typical Performance Characteristics

Figure 13. Turn-off Characteristics vs. Gate Resistance

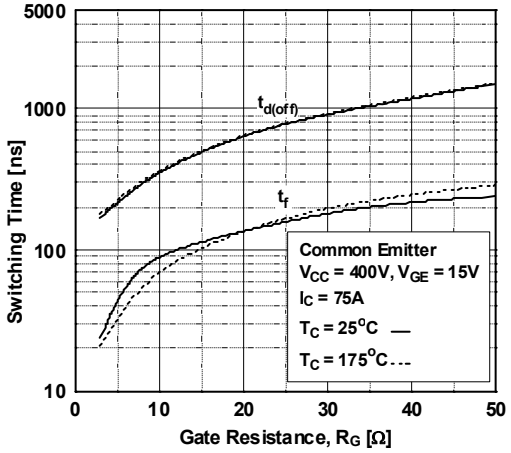


Figure 14. Turn-on Characteristics vs. Collector Current

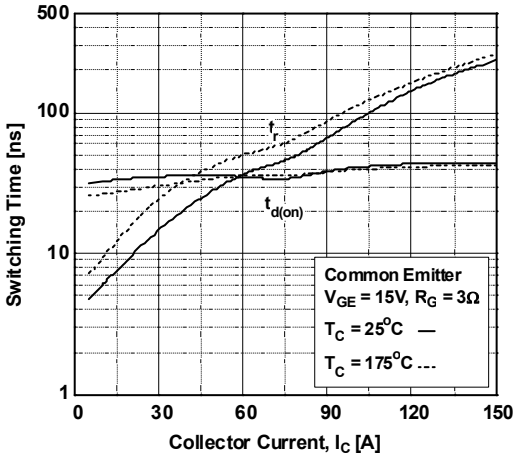


Figure 15. Turn-off Characteristics vs. Collector Current

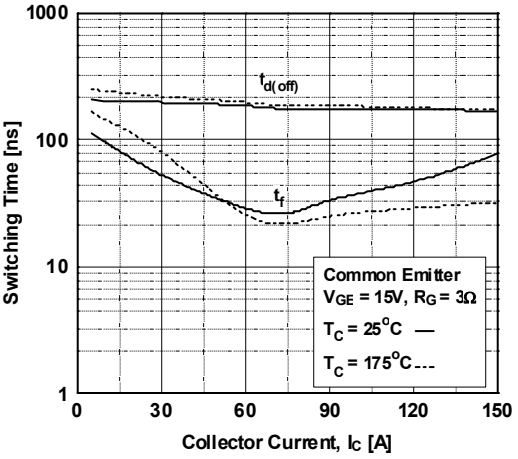


Figure 16. Switching Loss vs. Gate Resistance

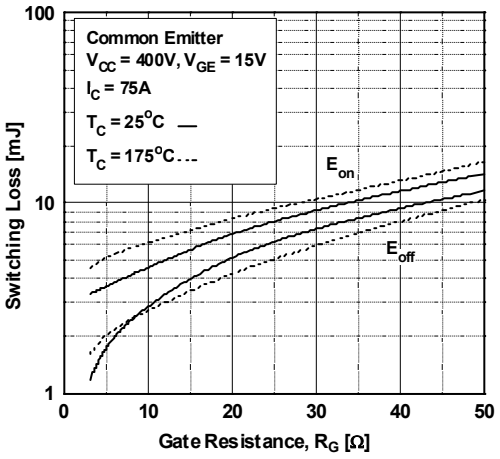


Figure 17. Switching Loss vs. Collector Current

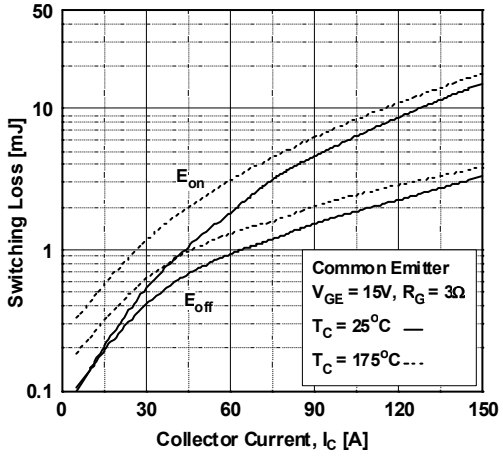
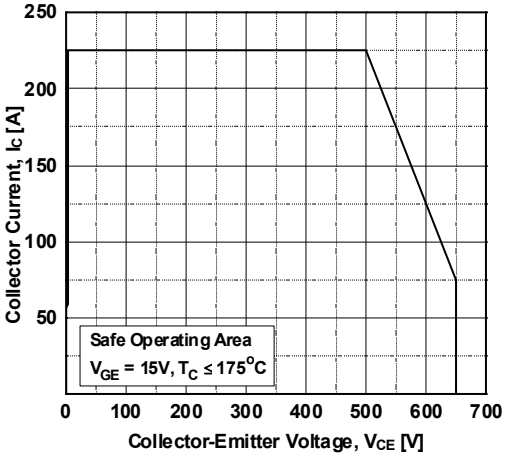


Figure 18. Turn off Switching SOA Characteristics



Typical Performance Characteristics

Figure 19. Current Derating

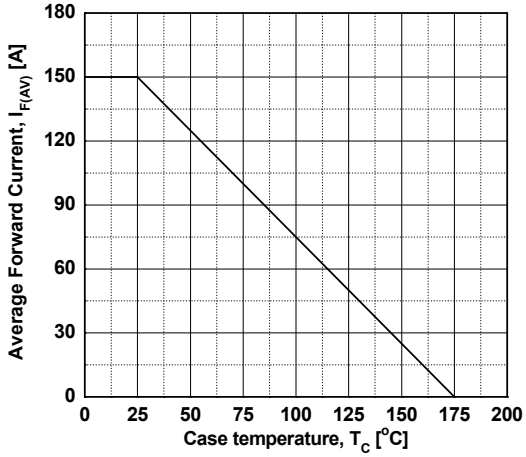


Figure 20. Load Current Vs. Frequence

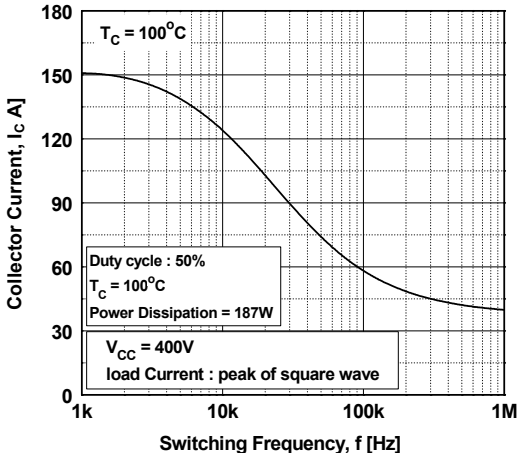


Figure 21. Forward Characteristics

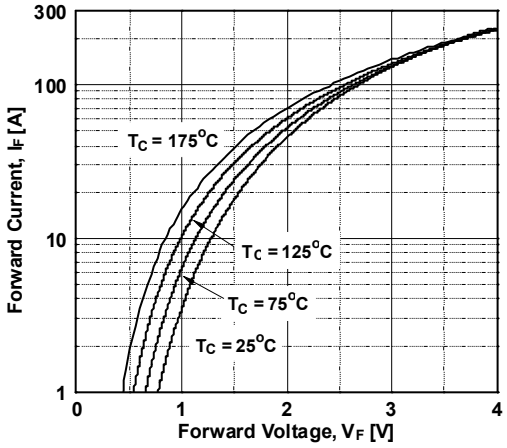


Figure 22. Reverse Recovery Current

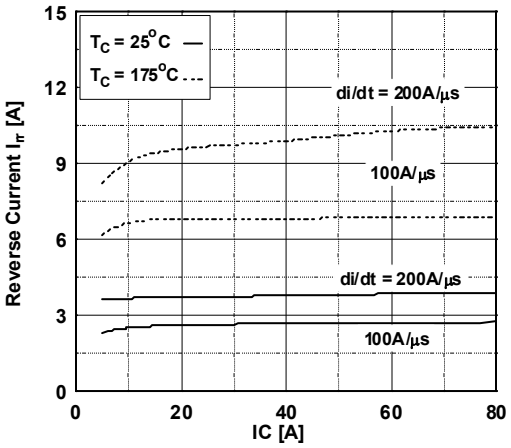


Figure 23. Stored Charge

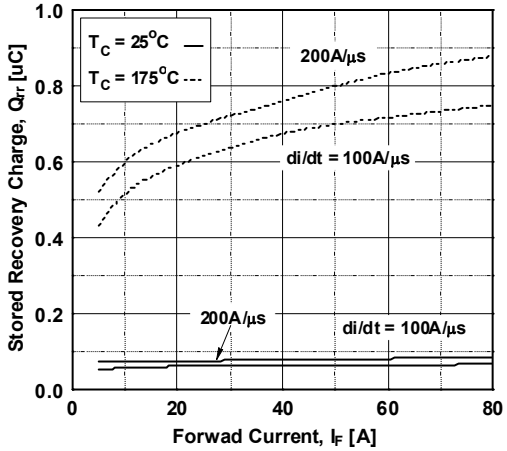
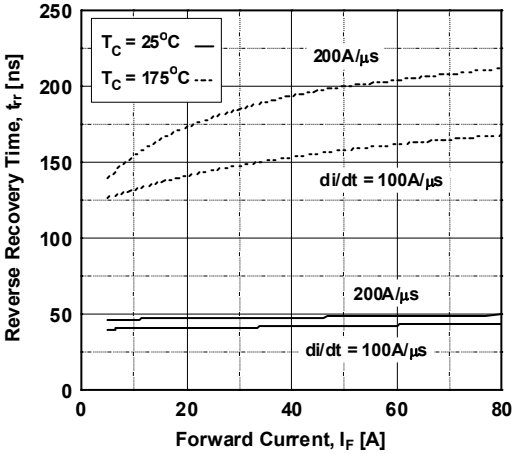


Figure 24. Reverse Recovery Time



Typical Performance Characteristics

Figure 25. Transient Thermal Impedance of IGBT

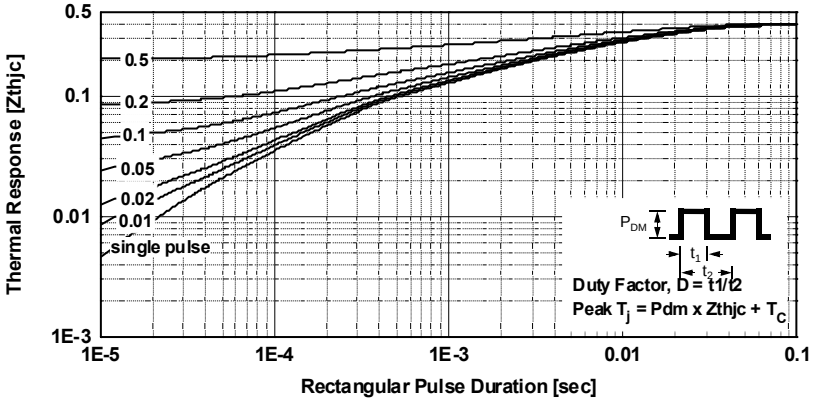
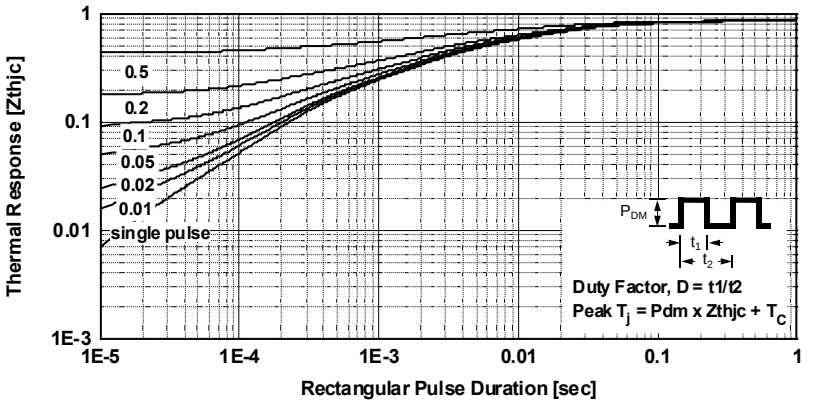
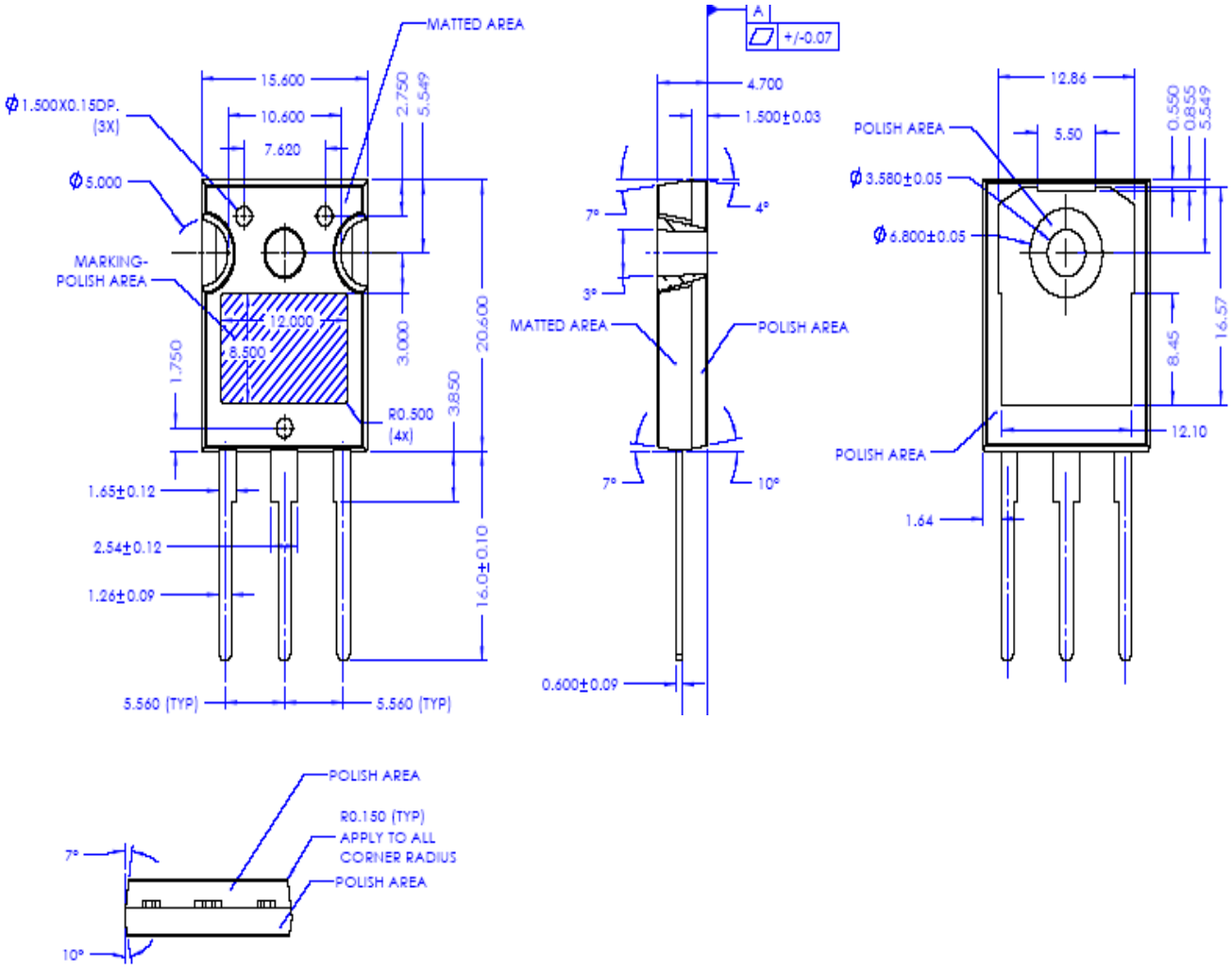


Figure 26.Transient Thermal Impedance of Diode



Mechanical Dimensions

TO - 247AB (FKS PKG CODE 001)



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